

REVISIONS			
LTR	DESCRIPTION	DATE (YR-MO-DA)	APPROVED
A	Inactivate case outline 3 for new design. Reduce supply voltage tolerance to 5 percent. Editorial changes throughout.	88 DEC 24	Michael A. Frye

CURRENT CAGE CODE 67238

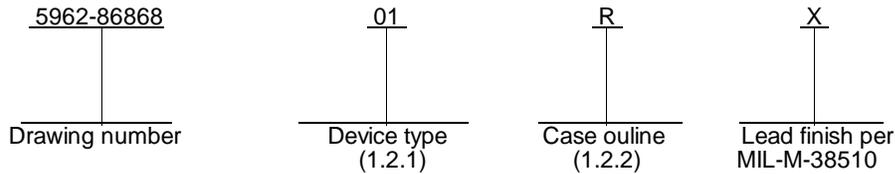
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REV STATUS OF SHEETS		REV	A	A	A	A	A	A	A	A	A	A	A	A	A	A	A	A	A	A
		SHEET	1	2	3	4	5	6	7	8	9	10	11	12	13	14				

PMIC N/A	PREPARED BY Todd D. Creek		DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444																
STANDARD MICROCIRCUIT DRAWING	CHECKED BY Ray Monnin																		
	APPROVED BY Michael A. Frye																		
	DRAWING APPROVAL DATE 18 DECEMBER 1986																		
	REVISION LEVEL A																		
THIS DRAWING IS AVAILABLE FOR USE BY ALL DEPARTMENTS AND AGENCIES OF THE DEPARTMENT OF DEFENSE		MICROCIRCUIT, DIGITAL, BIPOLAR, OCTAL BUS TRANSCEIVERS, MONOLITHIC SILICON																	
		SIZE A	CAGE CODE 14933	5962-86868															
AMSC N/A		SHEET 1 OF 14																	

1. SCOPE

1.1 Scope. This drawing describes device requirements for class B microcircuits in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices".

1.2 Part number. The complete part number shall be as shown in the following example:



1.2.1 Device type(s). The device type shall identify the circuit function as follows:

Device type	Generic number	Circuit function
01	8286	Octal bus transceiver, non-inverting
02	8287	Octal bus transceiver, inverting

1.2.2 Case outlines. The case outlines shall be as designated in appendix C of MIL-M-38510, and as follows:

Outline letter	Case outline
R	D-8 (20-lead, 1.060" x .310" x .200"), dual-in-line package
3	C-4 (28-terminal, .460" x .460" x .100"), square chip carrier package

1.3 Absolute maximum ratings.

Junction temperature (T_J)	-----	+200° C
Storage temperature range	-----	-65° C to +150° C
Output voltage	-----	-0.5 V dc to +5.5 V dc
Supply voltage range	-----	-0.5 V dc to +7.0 V dc
Input voltage	-----	-1.0 V dc to +5.5 V dc
Maximum power dissipation (P_D)	-----	1.0 W
Lead temperature (soldering, 10 seconds)	-----	+300° C
Thermal resistance, junction-to-case (θ_{JC}):		
Cases R and 3	-----	See MIL-M-38510, appendix C

1.4 Recommended operating conditions.

Case operating temperature range (T_C)	-----	-55° C to +125° C
Supply voltage range (V_{CC})	-----	+4.75 V dc to +5.25 V dc
Minimum high level input voltage (V_{IH})	-----	2.0 V dc
Maximum low level input voltage (V_{IL}):		
A port	-----	0.8 V dc
B port	-----	0.9 V dc

STANDARDIZED MILITARY DRAWING DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444	SIZE A		5962-86868
		REVISION LEVEL A	SHEET 2

2. APPLICABLE DOCUMENTS

2.1 Government specification, standard, and bulletin. Unless otherwise specified, the following specification, standard, and bulletin of the issue listed in that issue of the Department of Defense Index of Specifications and Standards specified in the solicitation, form a part of this drawing to the extent specified herein.

SPECIFICATION

MILITARY
MIL-M-38510 - Microcircuits, General Specification for.

STANDARD

MILITARY
MIL-STD-883 - Test Methods and Procedures for Microelectronics.

(Copies of the specification, standard, and bulletin required by manufacturers in connection with specific acquisition functions should be obtained from the contracting activity or as directed by the contracting activity.)

2.2 Order of precedence. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing shall take precedence.

3. REQUIREMENTS

3.1 Item requirements. The individual item requirements shall be in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices" and as specified herein.

3.2 Design, construction, and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-M-38510 and herein.

3.2.1 Terminal connections. The terminal connections shall be as specified on figure 1.

3.2.2 Truth table. The truth table shall be as specified on figure 2.

3.2.3 Logic diagram. The logic diagram shall be as specified on figure 3.

3.2.4 Case outlines. The case outlines shall be in accordance with 1.2.2 herein.

3.3 Electrical performance characteristics. Unless otherwise specified herein, the electrical performance characteristics are as specified in table I and shall apply over the full case operating temperature range.

3.4 Marking. Marking shall be in accordance with MIL-STD-883 (see 3.1 herein). The part shall be marked with the part number listed in 1.2 herein. In addition, the manufacturer's part number may also be marked as listed in 6.4 herein.

3.5 Certificate of compliance. A certificate of compliance shall be required from a manufacturer in order to be listed as an approved source of supply in 6.4. The certificate of compliance submitted to DESC-ECS prior to listing as an approved source of supply shall state that the manufacturer's product meets the requirements of MIL-STD-883 (see 3.1 herein) and the requirements herein.

3.6 Certificate of conformance. A certificate of conformance as required in MIL-STD-883 (see 3.1 herein) shall be provided with each lot of microcircuits delivered to this drawing.

STANDARDIZED MILITARY DRAWING DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444	SIZE A		5962-86868
		REVISION LEVEL A	SHEET 3

TABLE I. Electrical performance characteristics. 1/ 2/

Test	Symbol	Conditions -55°C ≤ T _C ≤ +125°C unless otherwise specified	Group A subgroups	Limits		Unit	
				Min	Max		
Input clamp voltage	V _{IC}	I _{IN} = -5 mA	1, 2, 3		-1	V	
Power supply current	I _{CC}	Device type 01, V _{CC} = 5.25 V	1, 2, 3		160	mA	
		Device type 02, V _{CC} = 5.25 V	1, 2, 3		130	mA	
Forward input current	I _F	V _F = 0.45 V, V _{CC} = 5.25 V	1, 2, 3		-0.2	mA	
Reverse input current	I _R	V _R = 5.25 V, V _{CC} = 5.25 V	1, 2, 3		50	μA	
Low level output voltage	V _{OL}	B outputs, I _{OL} = 20 mA, V _{CC} = 4.75 V	1, 2, 3		0.45	V	
		A outputs, I _{OL} = 10 mA, V _{CC} = 4.75 V	1, 2, 3		0.45	V	
High level output voltage	V _{OH}	B outputs, I _{OL} = -5 mA, V _{CC} = 4.75 V	1, 2, 3	2.4		V	
		A outputs, I _{OL} = -1 mA, V _{CC} = 4.75 V		2.4		V	
Output off current	I _{OFF}	V _{OFF} = 0.45 V, V _{CC} = 5.25 V	1, 2, 3		-0.2	mA	
		V _{OFF} = 5.25 V, V _{CC} = 5.25 V	1, 2, 3		50	μA	
High level input voltage 1/	V _{IH}		1, 2, 3	2.0		V	
Low level input voltage 1/	V _{IL}		A port	1, 2, 3		0.8	V
			B port	1, 2, 3		0.9	V

See footnote at end of table.

STANDARDIZED MILITARY DRAWING DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444	SIZE A		5962-86868
		REVISION LEVEL A	SHEET 4

TABLE I. Electrical performance characteristics. 1/ 2/

Test	Symbol	Conditions -55°C ≤ T _C ≤ +125°C 4.75 V ≤ V _{CC} ≤ 5.25 V unless otherwise specified		Group A subgroups	Limits		Unit
					Min	Max	
Input capacitance	C _{IN}	V _{CC} = 5.0 V V _{BIAS} = 2.5 V T _C = +25°C; f = 1 Mhz See 4.3.1c	OE, T	4		12	pF
			All others			25	pF
Functional tests		See 4.3.1d		7, 8			
Input to output delay 1/	t _{PLH} , t _{PHL}	B outputs, I _{OL} = 20 mA I _{OH} = -5 mA, C _L = 300 pF	Device type 01	9, 10, 11		25	ns
			Device type 02	9, 10, 11		35	ns
Output disable time 1/	t _{PLZ} , t _{PHZ}	A outputs, I _{OL} = 10 mA, I _{OH} = -1 mA, C _L = 100 pF (see figure 4), V _{CC} = 5.0 V		9, 10, 11		25	ns
Output enable time	t _{PZL} , t _{PZH}			9, 10, 11		50	ns
Output rise time	t _r	2.0 V to 0.8 V (see figure 4), V _{CC} = 5.0 V		9, 10, 11		20	ns
Output fall time	t _f	2.0 V to 0.8 V (see figure 4), V _{CC} = 5.0 V		9, 10, 11		12	ns
Transmit/receive setup time 1/	t _s			9, 10, 11	30		ns
Transmit/receive hold time 1/	t _h			9, 10, 11	25		ns

1/ Due to test equipment limitations, actual tested values may differ from those specified, but the specified limits are guaranteed.

STANDARDIZED MILITARY DRAWING DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444	SIZE A		5962-86868
		REVISION LEVEL A	SHEET 5

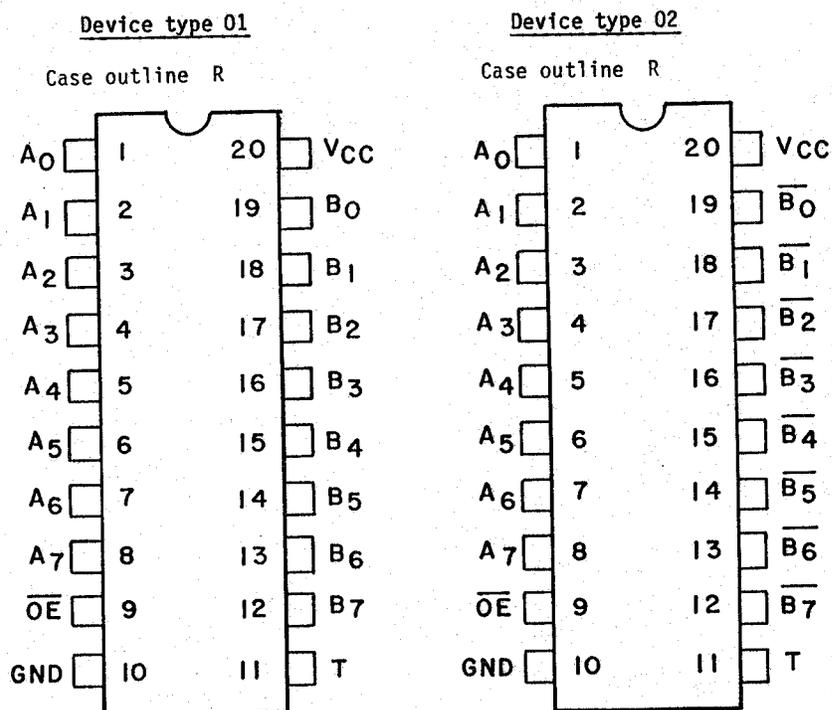


FIGURE 1. Terminal connections (top view).

STANDARDIZED
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DAYTON, OHIO 45444

SIZE
A

5962-86868

REVISION LEVEL
A

SHEET
6

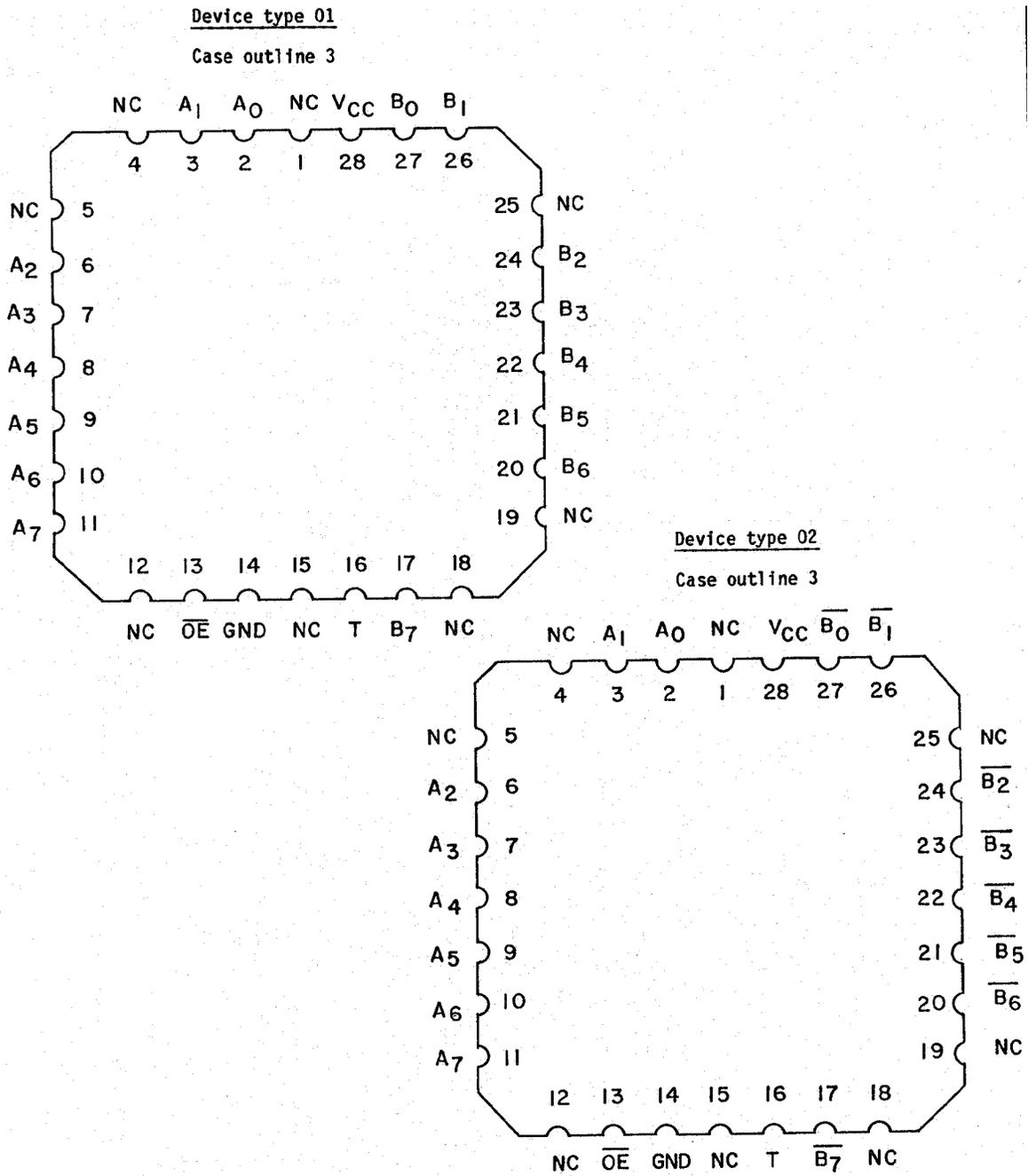


FIGURE 1. Terminal connections (top view) - Continued.

STANDARDIZED
MILITARY DRAWING
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DAYTON, OHIO 45444

SIZE
A

5962-86868

REVISION LEVEL
A

SHEET
7

Inputs	Conditions		
Chip disable	0	0	1
Transmit/Receive	0	1	X
A Port	Out	In	Hi-Z
B Port	In	Out	Hi-Z

FIGURE 2. Truth table.

STANDARDIZED MILITARY DRAWING DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444	SIZE A		5962-86868
		REVISION LEVEL A	SHEET 8

Device type 01

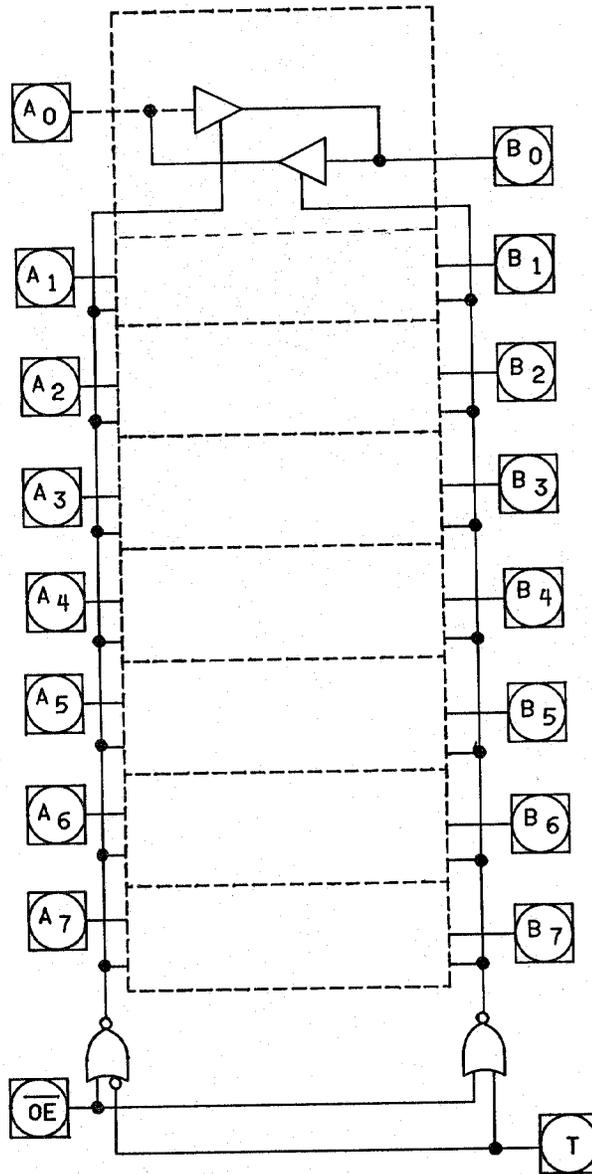


FIGURE 3. Logic diagrams.

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DAYTON, OHIO 45444

SIZE
A

5962-86868

REVISION LEVEL
A

SHEET
9

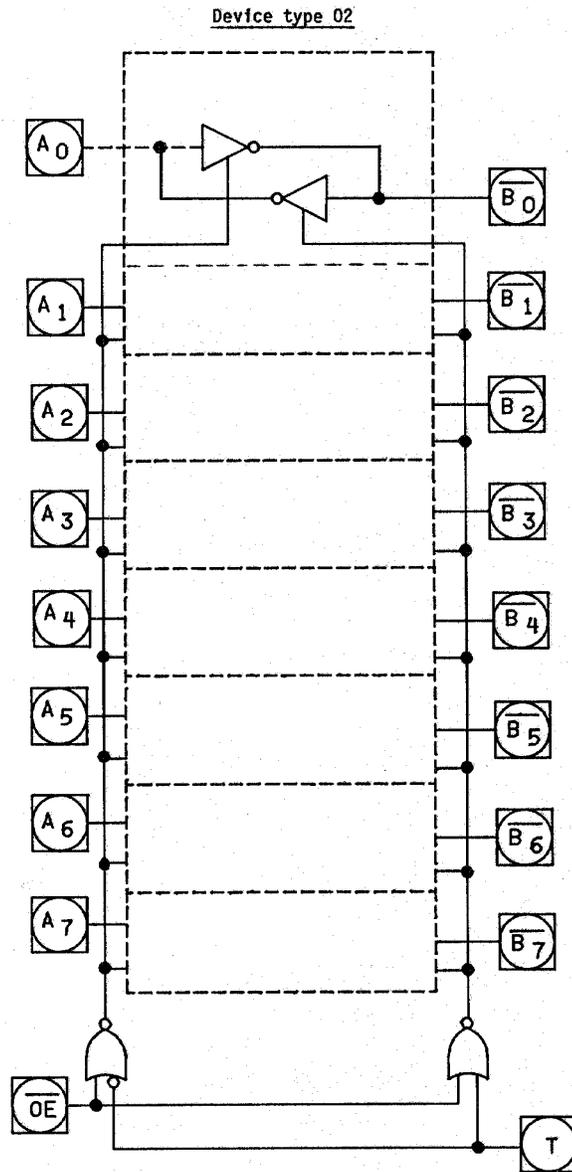


FIGURE 3. Logic diagrams - Continued.

STANDARDIZED
MILITARY DRAWING
DEFENSE ELECTRONICS SUPPLY CENTER
DAYTON, OHIO 45444

SIZE
A

5962-86868

REVISION LEVEL
A

SHEET
10

TEST CIRCUIT A OUTPUT TEST CIRCUIT B OUTPUT

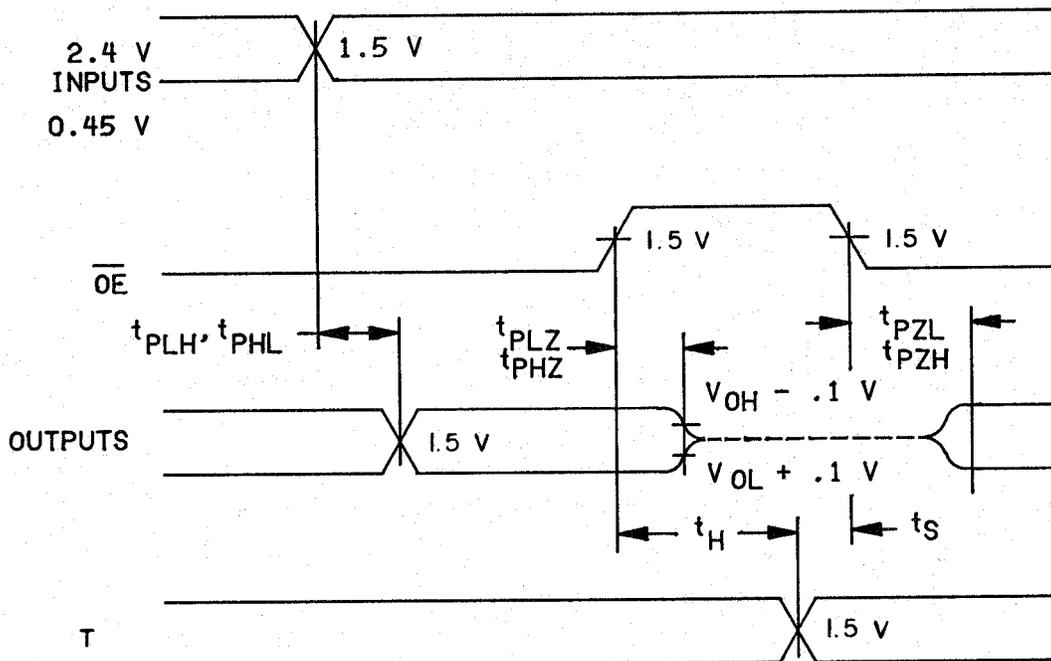
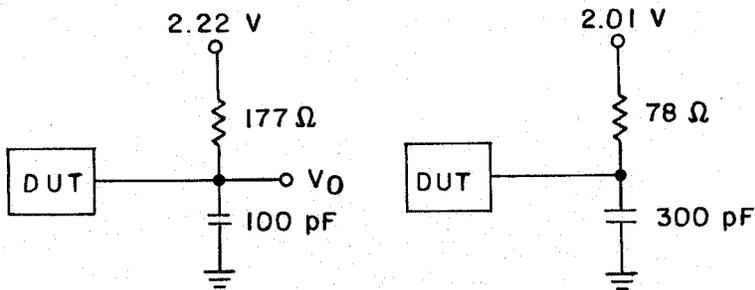


FIGURE 4. Switching time waveforms and test circuits.

STANDARDIZED
MILITARY DRAWING
DEFENSE ELECTRONICS SUPPLY CENTER
DAYTON, OHIO 45444

SIZE
A

5962-86868

REVISION LEVEL
A

SHEET
11

3.7 Notification of change. Notification of change to DESC-ECS shall be required in accordance with MIL-STD-883 (see 3.1 herein).

3.8 Verification and review. DESC, DESC's agent, and the acquiring activity retain the option to review the manufacturer's facility and applicable required documentation. Offshore documentation shall be made available onshore at the option of the reviewer.

4. QUALITY ASSURANCE PROVISIONS

4.1 Sampling and inspection. Sampling and inspection procedures shall be in accordance with section 4 of MIL-M-38510 to the extent specified in MIL-STD-883 (see 3.1 herein).

4.2 Screening. Screening shall be in accordance with method 5004 of MIL-STD-883, and shall be conducted on all devices prior to quality conformance inspection. The following additional criteria shall apply:

- a. Burn-in test (method 1015 of MIL-STD-883).
 - (1) Test condition A, B, C or D using the circuit submitted with the certificate of compliance (see 3.5 herein).
 - (2) $T_A = +125^\circ\text{C}$, minimum.
- b. Interim and final electrical test parameters shall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.

4.3 Quality conformance inspection. Quality conformance inspection shall be in accordance with method 5005 of MIL-STD-883 including groups A, B, C, and D inspections. The following additional criteria shall apply.

4.3.1 Group A inspection.

- a. Tests shall be as specified in table II herein.
- b. Subgroups 5 and 6 in table I, method 5005 of MIL-STD-883 shall be omitted.
- c. Subgroup 4 (C_{IN} measurement) shall be measured only for the initial test and after process or design changes which may affect input capacitance. A minimum sample size of 5 devices with zero rejects shall be required.
- d. Subgroup 7 and 8 functional tests shall verify the truth table.

4.3.2 Groups C and D inspections.

- a. End-point electrical parameters shall be as specified in table II herein.
- b. Steady-state life test conditions, method 1005 of MIL-STD-883.
 - (1) Test condition A, B, C, or D using the circuit submitted with the certificate of compliance (see 3.5 herein).
 - (2) $T_A = +125^\circ\text{C}$, minimum.
 - (3) Test duration: 1,000 hours, except as permitted by method 1005 of MIL-STD-883.

STANDARDIZED MILITARY DRAWING DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444	SIZE A		5962-86868
		REVISION LEVEL A	SHEET 12

TABLE II. Electrical test requirements.

MIL-STD-883 test requirements	Subgroups (per method 5005, table I)
Interim electrical parameters (method 5004)	---
Final electrical test parameters (method 5004)	1*, 2, 3, 7, 8 9, 10, 11
Group A test requirements (method 5005)	1, 2, 3, 4, 7, 8, 9, 10, 11
Groups C and D end-point electrical parameters (method 5005)	2, 8A, 10

* PDA applies to subgroup 1.

5. PACKAGING

5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-M-38510.

6. NOTES

6.1 Intended use. Microcircuits conforming to this drawing are intended for use when military specifications do not exist and qualified military devices that will perform the required function are not available for OEM application. When a military specification exists and the product covered by this drawing has been qualified for listing on QPL-38510, the device specified herein will be inactivated and will not be used for new design. The QPL-38510 product shall be the preferred item for all applications.

6.2 Replaceability. Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.

6.3 Comments. Comments on this drawing should be directed to DESC-ECS, Dayton, Ohio 45444, of telephone 513-296-5375.

STANDARDIZED MILITARY DRAWING DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444	SIZE A		5962-86868
		REVISION LEVEL A	SHEET 13

6.4 Approved sources of supply. Approved sources of supply are listed herein. Additional sources will be added as they become available. The vendors listed herein have agreed to this drawing and a certificate of compliance (see 3.5 herein) has been submitted to DESC-ECS.

Military drawing part number	Vendor CAGE number	Vendor similar part number <u>1/</u>
5962-8686801RX	34649	MD8286/B
5962-86868013X <u>2/</u>		MR8286/B
5962-8686802RX	34649	MD8287/B
5962-86868023X <u>2/</u>		MR8287/B

- 1/ Caution. Do not use this number for item acquisition. Items acquired to this number may not satisfy the performance requirements of this drawing.
- 2/ Inactive for new design. Not available from an approved source.

Vendor CAGE number

34649

Vendor name and address

Intel Corporation
3065 Bowers Avenue
Santa Clara, CA 95051

STANDARDIZED MILITARY DRAWING DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444	SIZE A		5962-86868
		REVISION LEVEL A	SHEET 14